

# Unique Dry Film Photoresist System for TSV Via Formation/Protection/Plating

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DuPont APL ATG Specialist

Solutions for Innovation



*The miracles of science™*

# Content

- **3D-TSV/TSV Process Overview**
- **Advantages of using dry film photoresist**
- **Dry film photoresist for 3D-TSV Process**
- **Summary**

# Our Mission

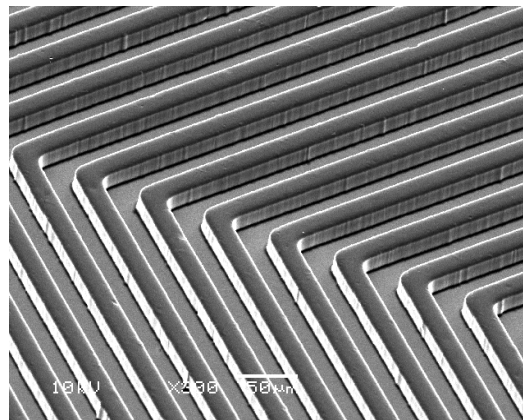
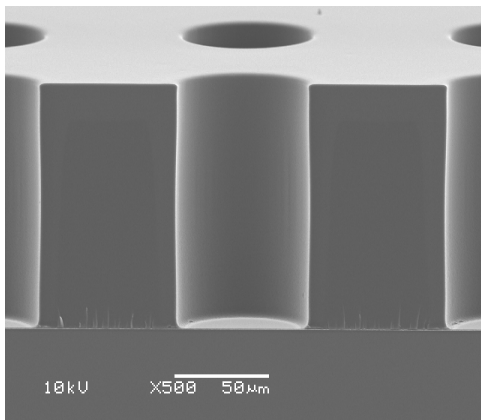


To enhance customers' competitiveness and profitability by offering

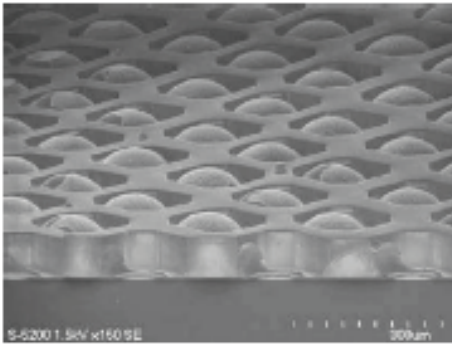
**Application knowledge**

**Materials**

**Integrated Process Technology**

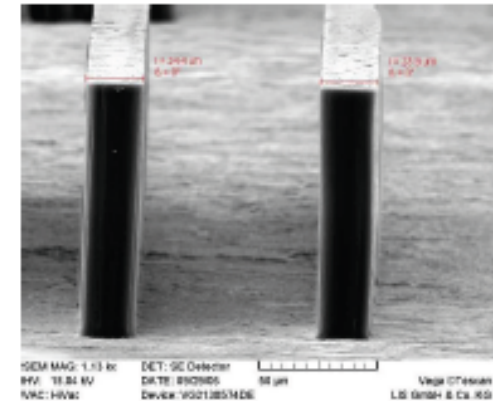


# DuPont Lithography Material Features



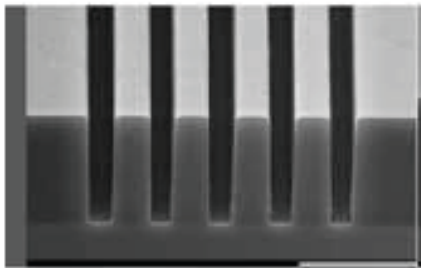
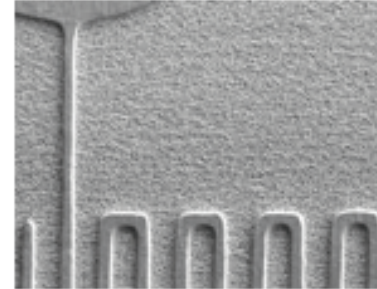
## High Aspect Ratio Imaging

- Thick polymer films (50-120um) for thick plating and stencil applications
- Strong heat resistance
- Clean removal



## Fine Feature Imaging

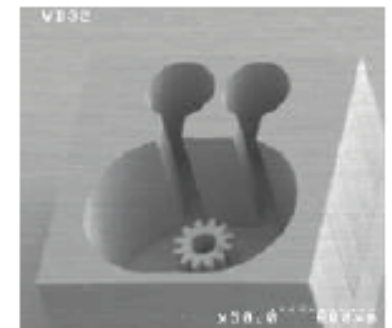
- Thin polymer films (10-30um) for high definition plating and etching applications



5  $\mu$ m

## High Definition Permanent Dielectrics

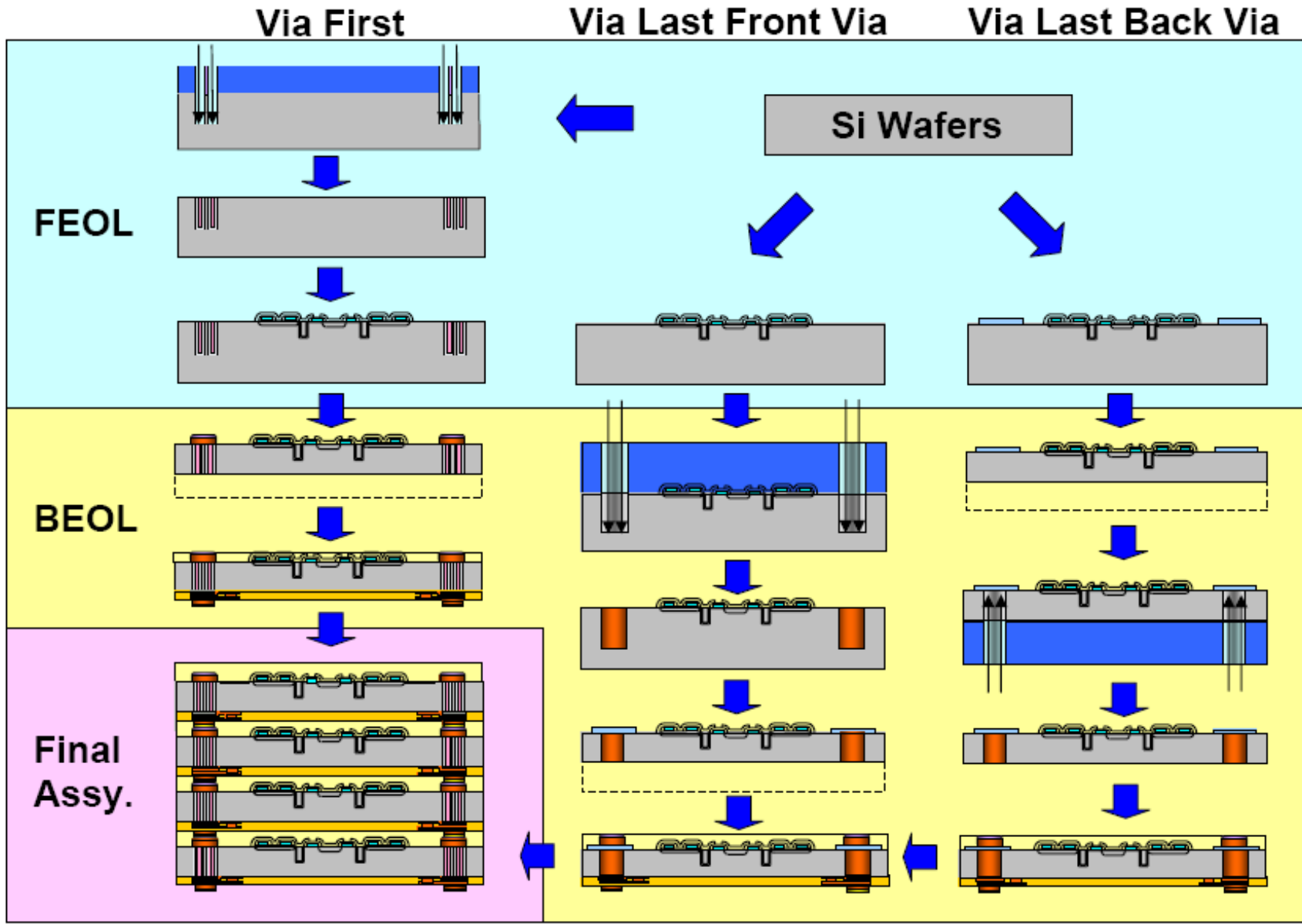
- Polymer films for permanent structuring and dielectric applications



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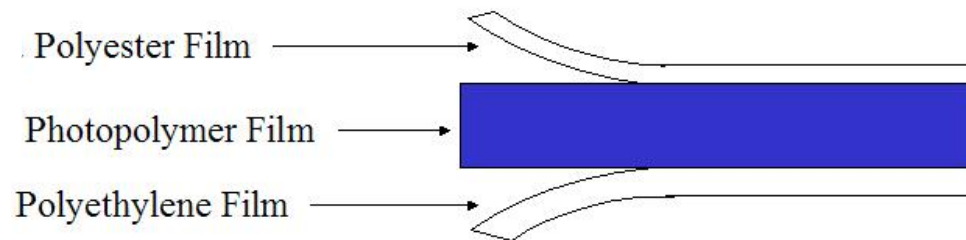
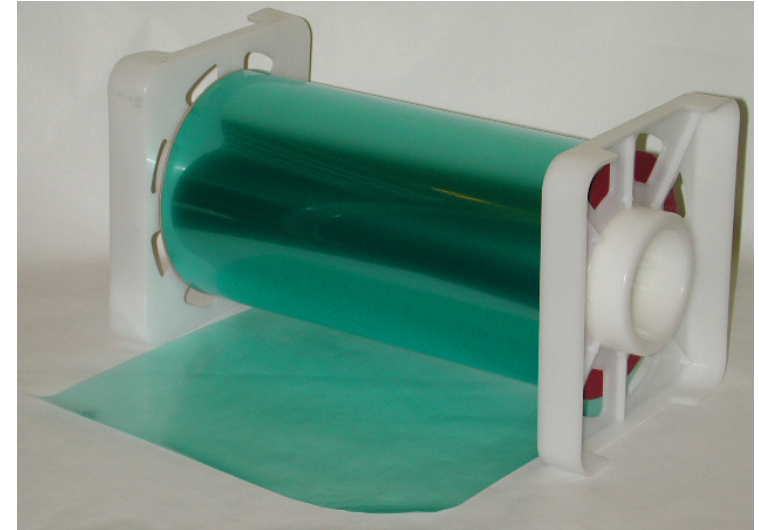
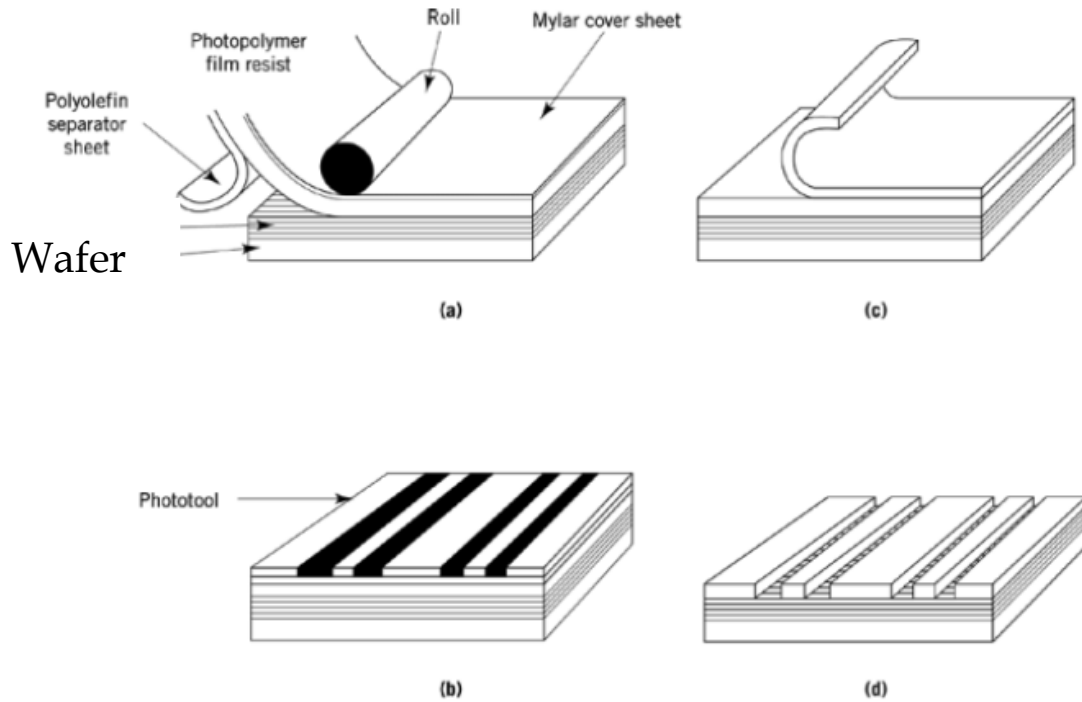
# 3D-TSV/TSV Process Overview



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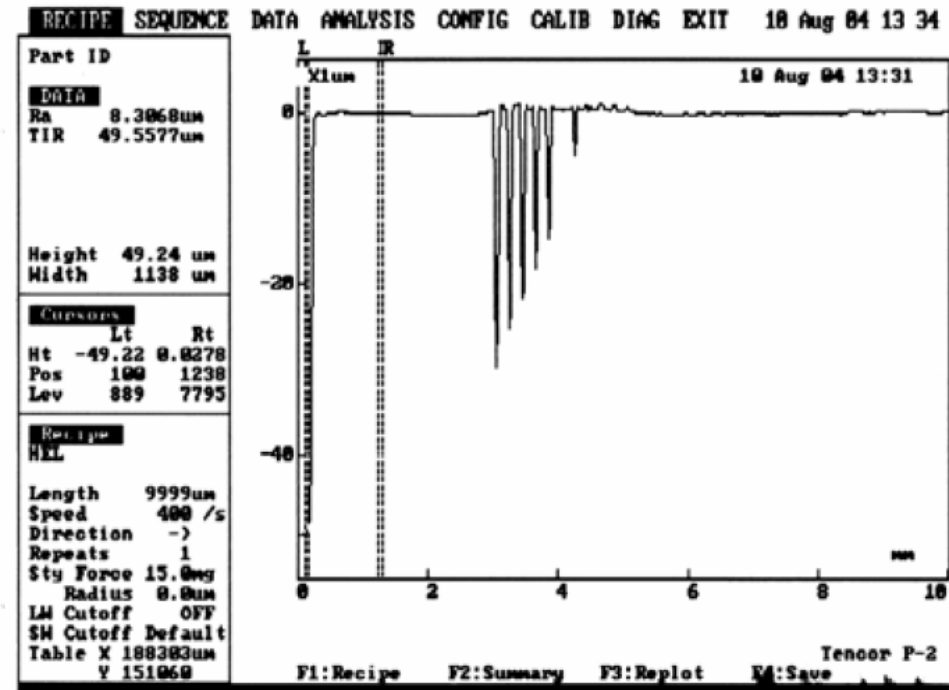
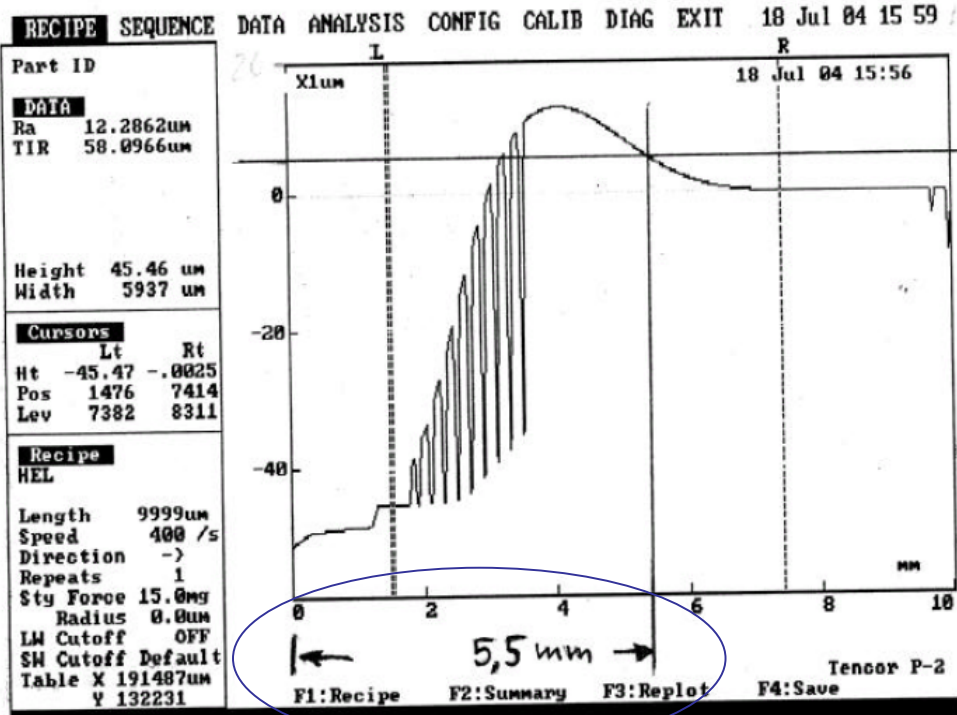
# Dry Film process





# DuPont MPF™ Microlithographic Polymer Films

No Edge Bead



**Spin on Liquid**

**MPF™**  
Microlithographic Polymer Film

**5.5 mm less usable area due to edge bead**

**Maximized usable area**

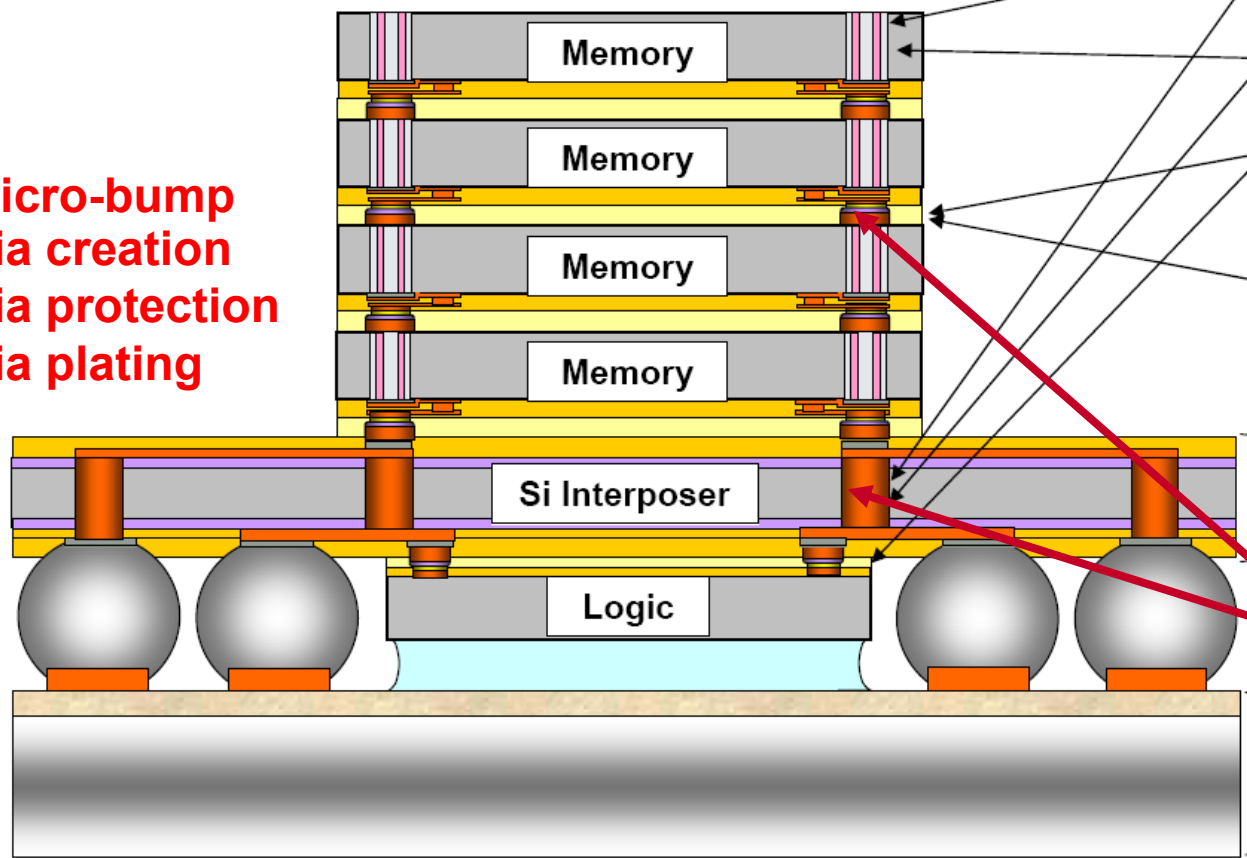
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# Integrated Solution on 3D-TSV device

*WOW-TSV Memory / Logic SiP module*

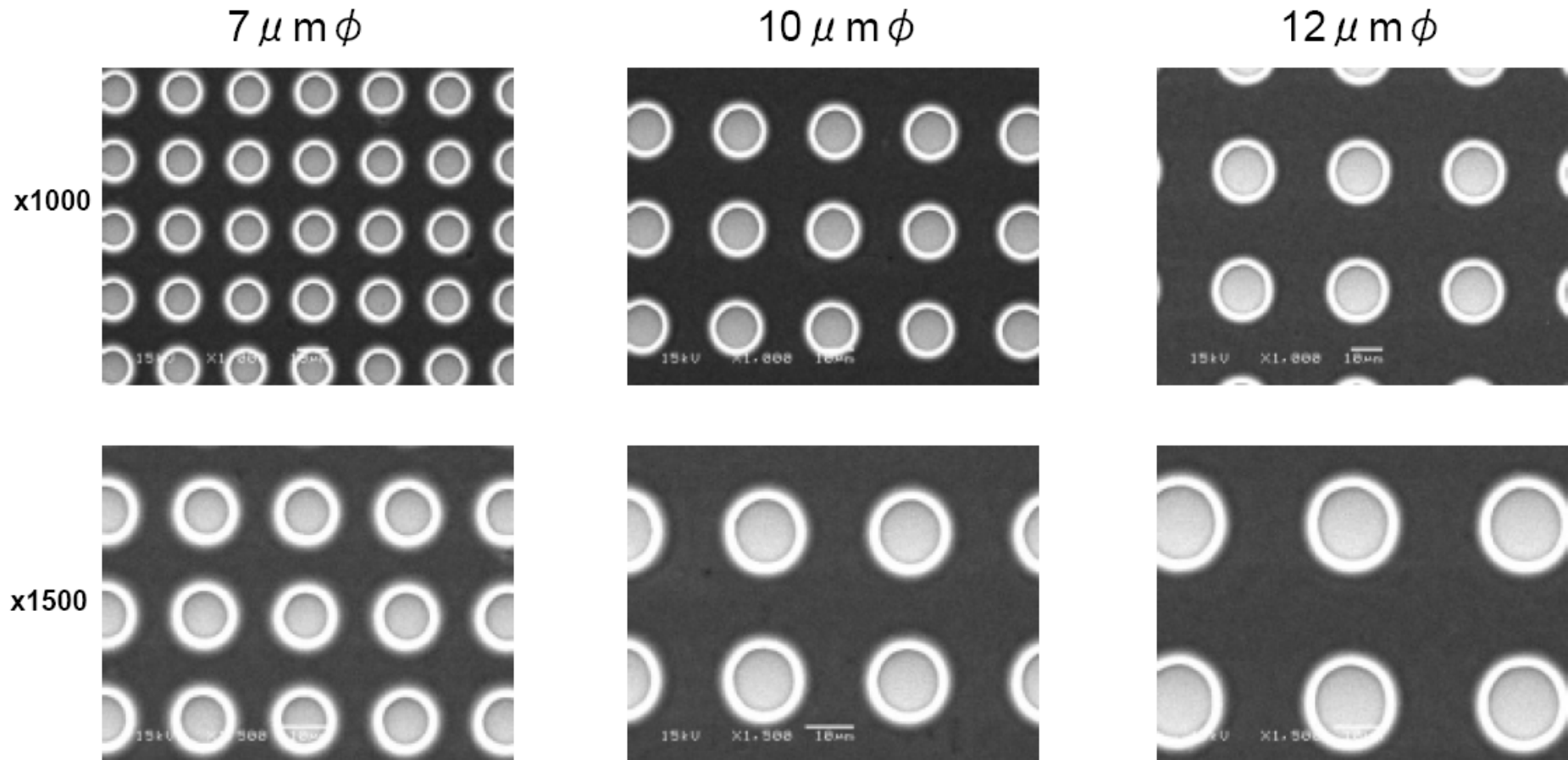
**Micro-bump  
Via creation  
Via protection  
Via plating**



- Zyron®  
Depo. Cleaning gas  
Dry etching gas
- Vertrel®  
CF deposition  
Cleaning agents
- XP-3000/XP-7000 series  
Wafer level Polyimide  
Underfill
- Syton® Mazin®  
BG polish  
Wafer polish  
EKC series  
PCMP cleaner  
Dryfilm/Thick PR  
Remover & Chemicals
- HD series  
Photo sensitive  
Polyimide coatings
- APL /WB/ MX series  
Dry Film photoresist**
- Coolam™  
Thermo conductive/  
Thermal resistant  
Substrate system

# Via Creation

## DuPont® Ultrathin Dry Film for small via ( 7-10 $\mu\text{m}$ )

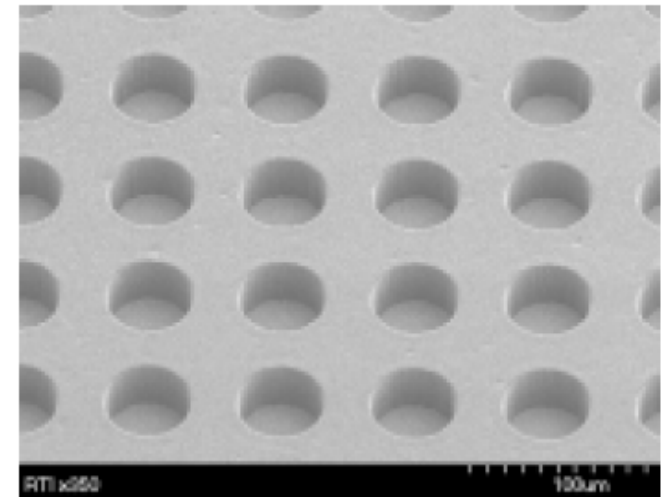
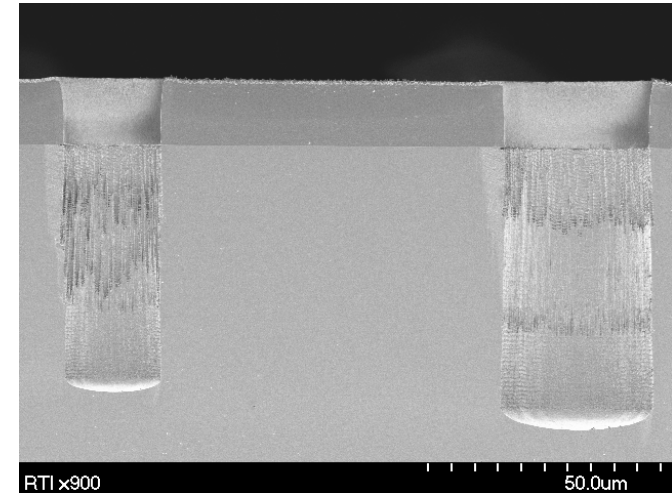
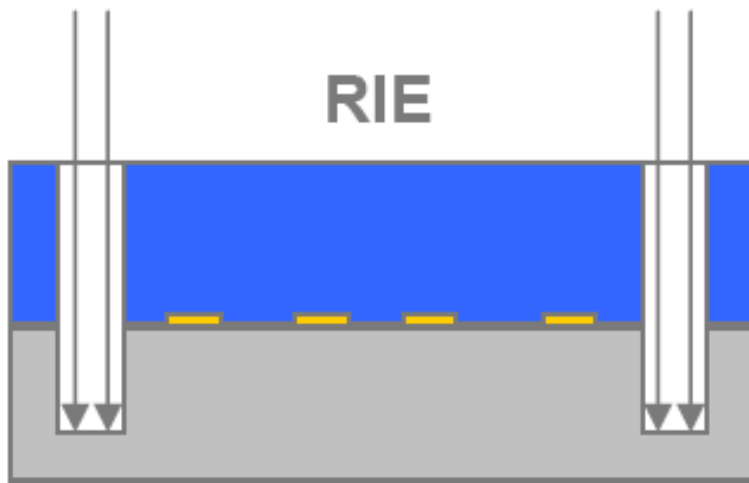


# MX5000 series

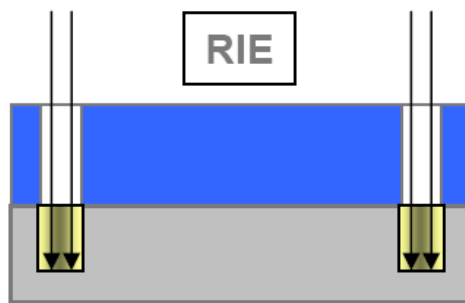
Via Creation

DuPont® MX5000 Dry Film Photoresist

- ◆ One step application process
- ◆ High selectivity to DRIE process (>100:1)
- ◆ High temperature resistance (>200C)
- ◆ Thickness uniformity ( $\pm 2\%$ )

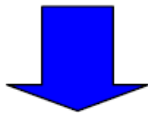


# An example of Via creation process scheme



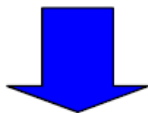
Deep RIE / Bosch process

- **MX5000series** Dry Film Photoresist
- **Zyron®** high purity fluorine containing gases



Resist removal process

- **EKC WLP series** ® Dry Film Remover



CF deposition removal process

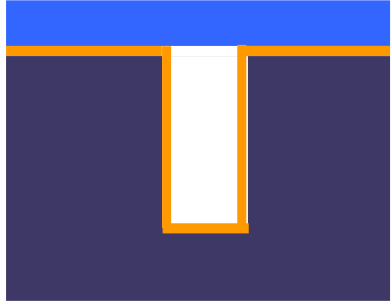
- **Vertrel® XF (C5H2F10)** CF deposition remover
- **EKC265, EKC2255** residue remover

# Via Protection & Via Plating



# Process limitation of liquid photoresist

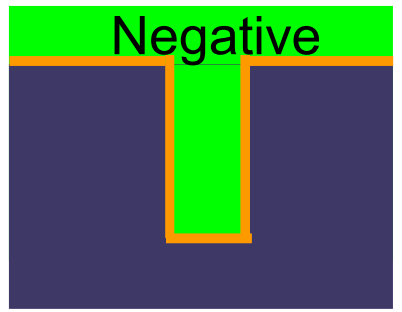
Via Tenting  
-No PR in  
the via



Lamination  
←

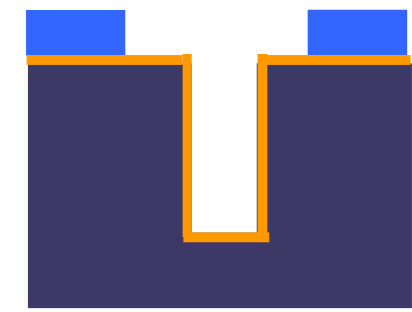
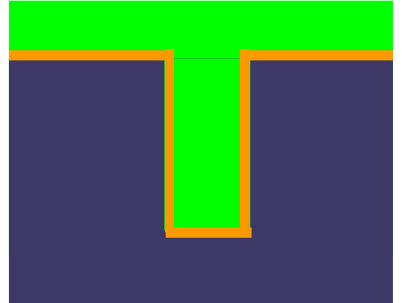
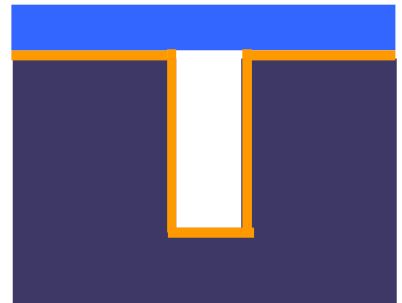


Spin Coat  
→



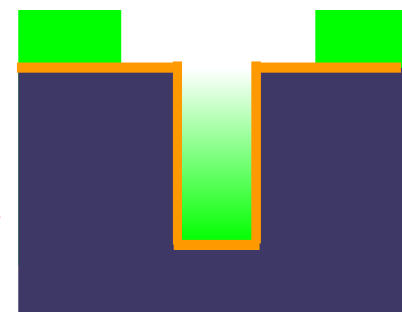
Coating  
bubbles  
in via

Silicon Via/Trench



Mild chemical for  
Development  
- 1% Na<sub>2</sub>CO<sub>3</sub>/K<sub>2</sub>CO<sub>3</sub>

Harsh chemical for  
Development  
- TMAH: copper etch  
- KOH: Al etch



Development  
residue in via

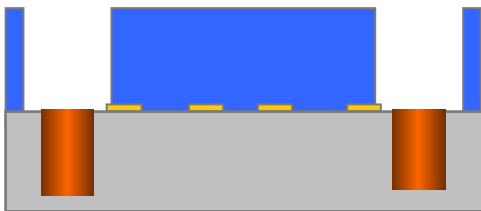


# MX5000 series

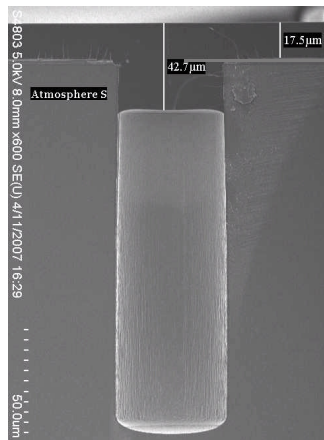
## Via Plating

## DuPont® MX5000 Dry Film Photoresist

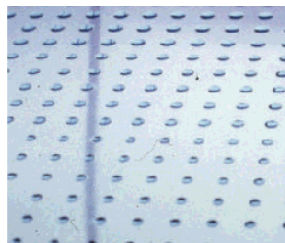
### Plating



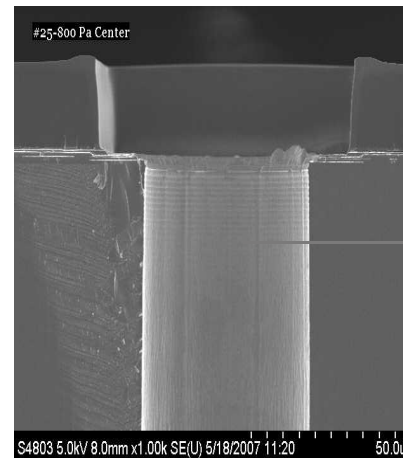
- One step, simple application process
- “Tenting” over vias
- No Residue inside the vias



Dry film  
“tenting” over  
existing vias



After Lamination

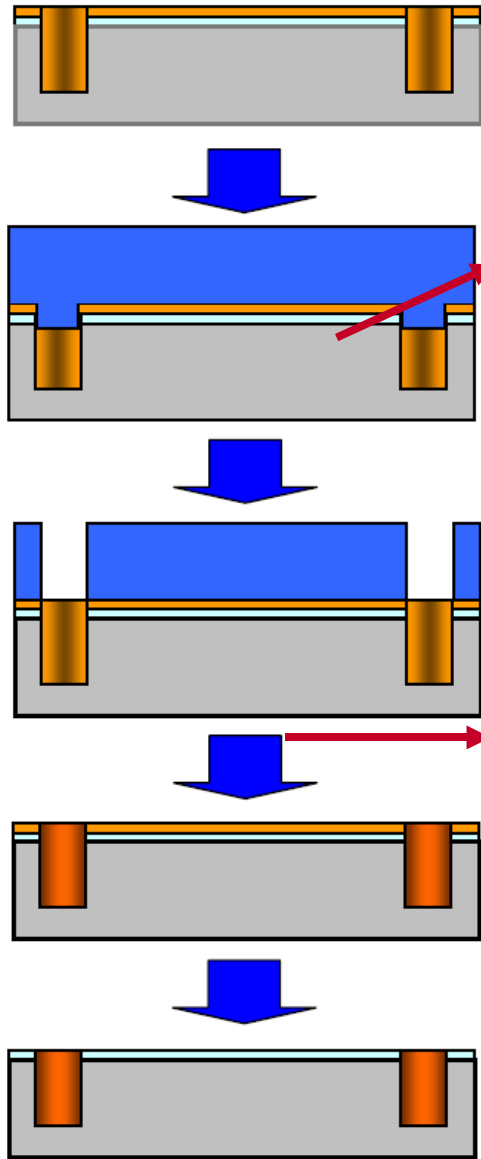


Residue free via  
ready for plating

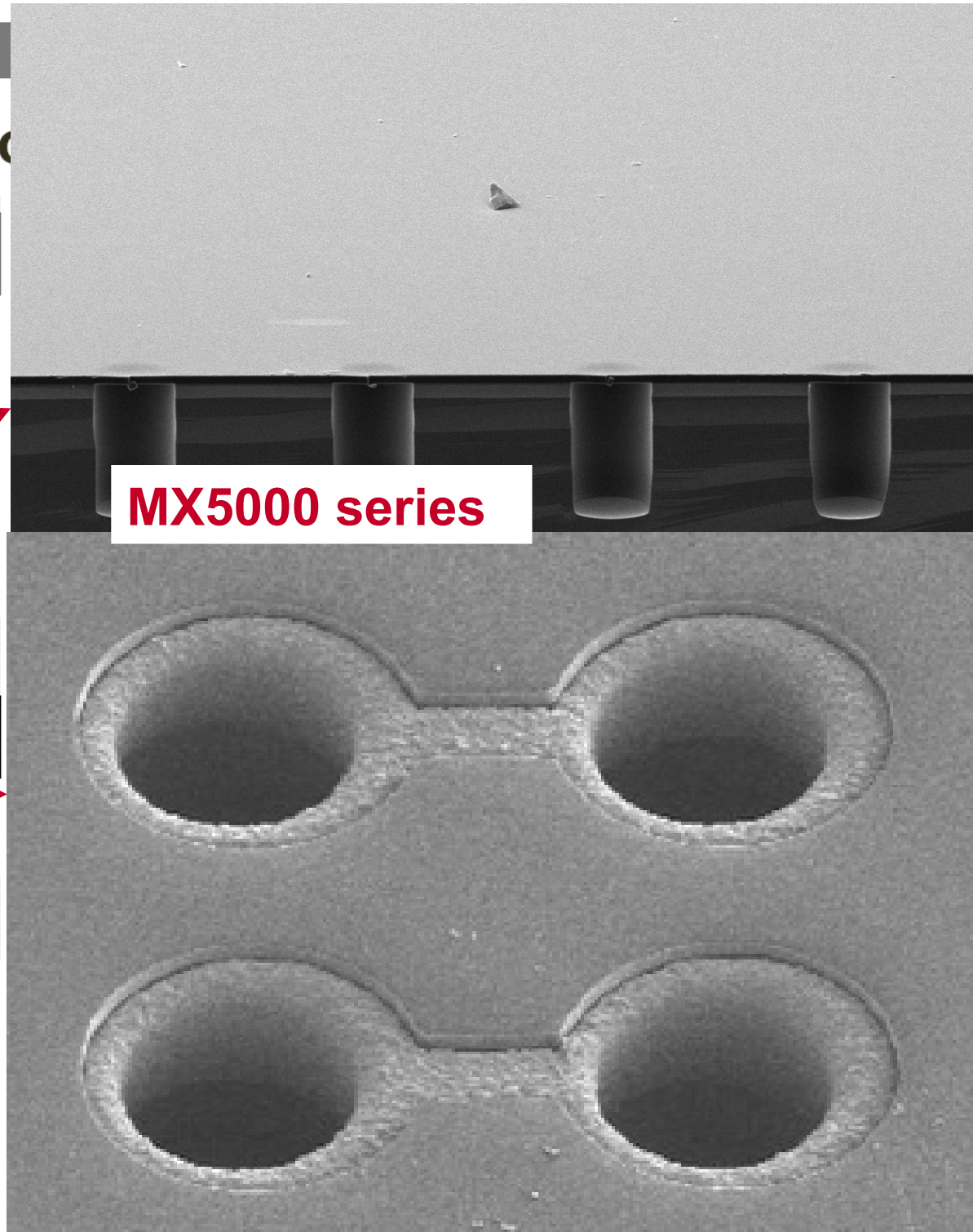
After Development

# An example of

st)



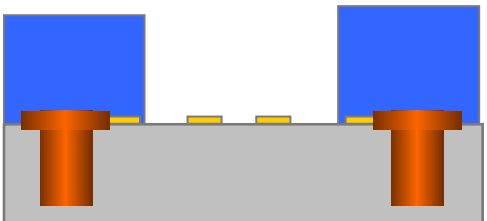
**MX5000 series**



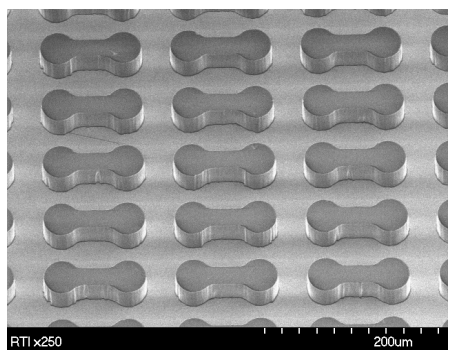
# Via Protection

## DuPont® MX5000 Dry Film Photoresist

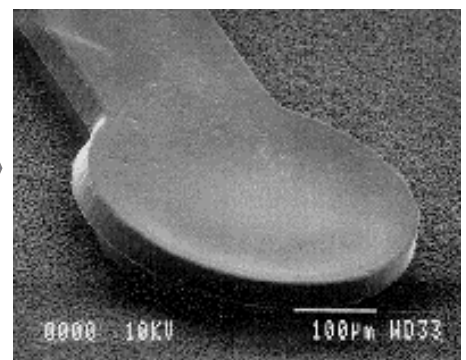
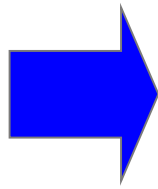
### Rerouting



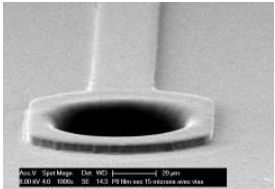
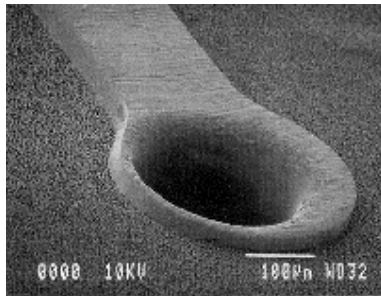
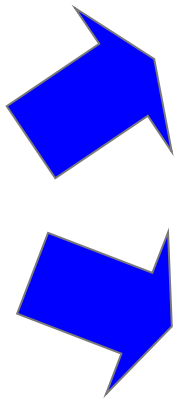
- One step, simple application process
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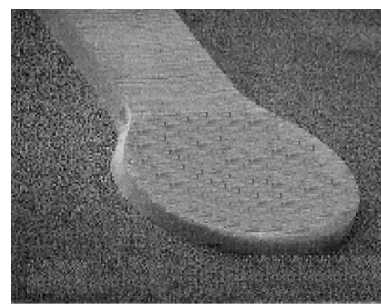
Dog Bone Structure after development



Dog Bone Structure after metal etch



Protected unfilled via after removal

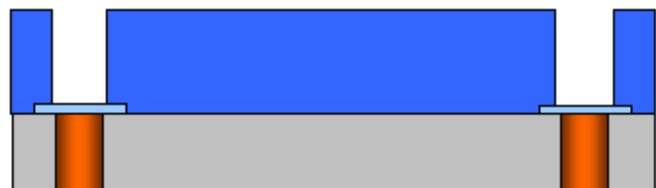


Protected filled via after removal



# Micro Bump & Cu Pillar

# An example of Bump process scheme



Electric plating process

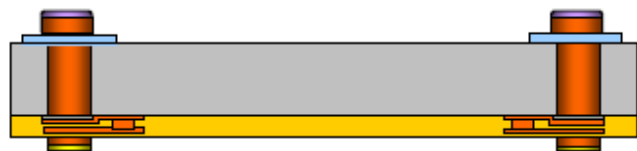
- WBR2050 series Dryfilm Plating mask



Resist removal process

- EKC WLP series ® Dry Film Remover

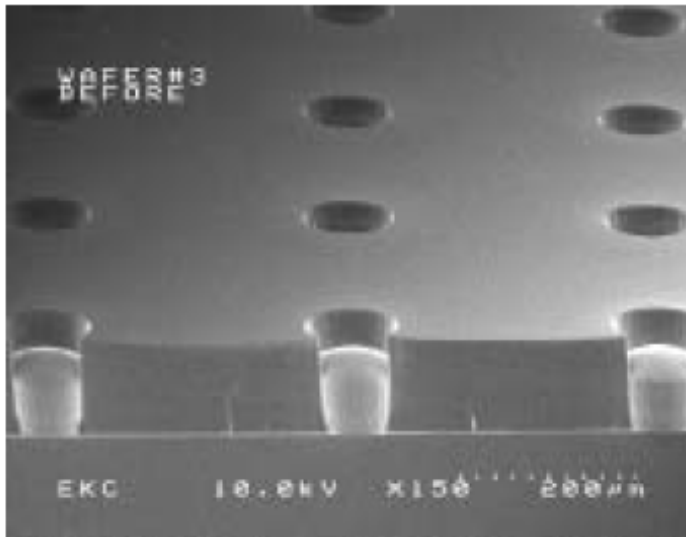
Backside  
Bump



Re-routing process

- HD4100/HD8820 series PI coatings

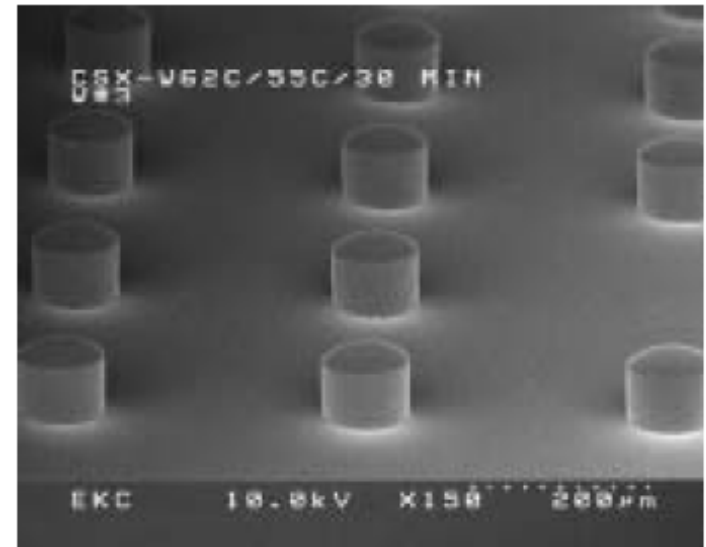
## DuPont® WBR2050 series



**Photoresist:**  
MPF™WBR50

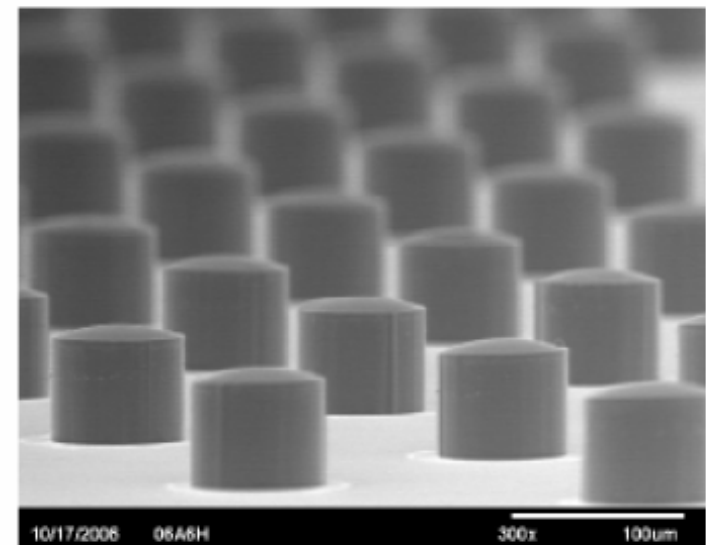
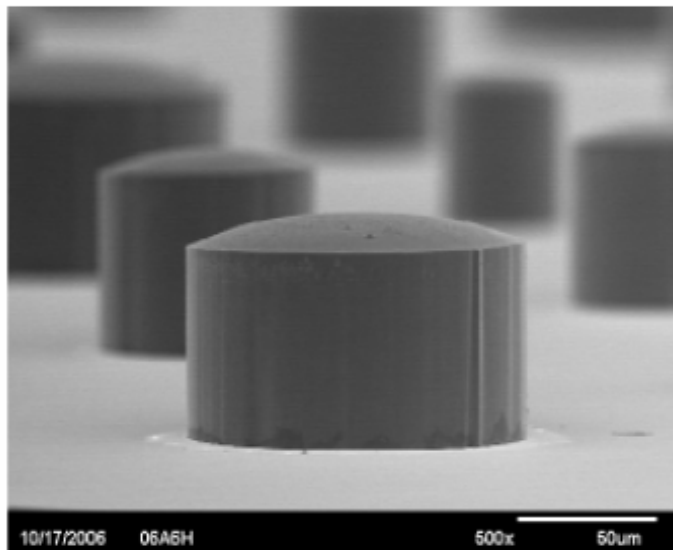
**Surface:**  
Cu

**Exposure:**  
Suss MA200



**Plating Eletrolytes:**  
Nexx Plating Tool  
(Vertical Plating)  
RH 8540

**Remover**  
DuPont EKC WLP™



Courtesy of Nexx Systems

# Summary



# Superior properties of dry film photoresist

## 1. Photoresist Lamination / Exposure / Development

- Fast throughput
- Excellent dimension control
- Good resolution
- Wider operation window
- Mild chemical compatible process (Metal corrosion-free Chemicals)

## 2. Via Etching

- High selectivity in via etching process
- No Cracking or Pull-back during etching process
- Residue-free after via etching process

## 3. Plating & Tenting (Via Filling and Micro Connection Metal Deposition)

- Good Plating capability
- Residue-free development

## 4. Stripping

- Excellent Stripping capability

 **One DuPont Solution for TSV!**





*The miracles of science™*